

Search Notes**Application/Control No.**

10/801,706

Examiner

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Applicant(s)/Patent under Reexamination

PAN, WUN-FANG

Art Unit

2875

SEARCHED

Class	Subclass	Date	Examiner
362	640	7/11/2004	EPD
362	647	7/11/2004	EPD
362	652	7/11/2004	EPD
362	653	7/11/2004	EPD
362	654	7/11/2004	EPD
362	806	7/11/2004	EPD

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class and subclass search in east combined with keywords, see attachment	7/11/2004	EPD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner